

Notice of References Cited		Application/Control No. 10/530,169	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
		Examiner Dean Kwak	Art Unit 1797	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,595,636	01-1997	Franzen, Jochen	204/464
	B	US-			
	C	US-			
	D	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Feld et al., Comparative and Complementary Plasma Desorption Mass Spectrometry/Secondary Ion Mass Spectrometry Investigations of Polymer Materials, Anal. Chem. 1991, 63, 903-910.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.